

AMB1831

Open Short Tester (Up to 4096 Channels)



Highlight

Amoeba® AMB1831 is a true multi-sites tester with the fastest test time in the industry designed for an effective open - short test; pin-to-pin measurement as fast as 2.5ms.

As required in standard continuity test, AM1831 offers cost effective test solutions for open circuits or short circuits in the device pins at package or wafer level. It can be integrated with automated handler and die sorter. In terms of software, techFlow offers an overall friendly user experience with data binning and simple test programme for easy editing via tsv file.

AMB1831 offers absolute cost effective solutions and a definite ease of test development for overall Open/Short Testing. Customers no longer need an ATE just for an OS Screening, hence putting the ATE back for intended effective use.

Purpose

Pin-to-GND	Pin-to-Pin	Current	Resistance
◆	◆	◆	◆

Feature

Product Features	Specifications
Total Channels	Up to 4096 Channels
Maximum Voltage	10 V
Maximum Current	50 mA
Multisite Testing	Yes
Programming Language	Test Development Tool
PC Interface	USB 2.0 (480Mbps)

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Test Function

Test Condition, V/I	Pin-to-ALL-GND	Pin-to-Pin
Similar Setting	2.5ms	2.5ms
Flexible Setting	5.0ms	5.5ms

Voltage Source/Measure Accuracy

Range (±V)	Typical Accuracy (± A)
2.5V	5mV + 0.2% of value
10.0V	10mV + 0.1% of value

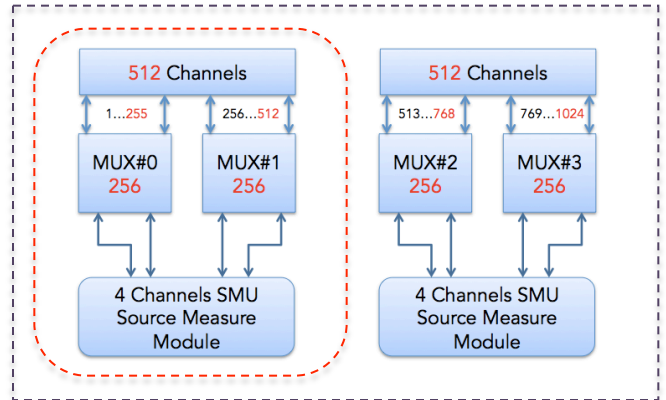
Current Source/Measure Accuracy

Range (±V)	Typical Accuracy (± A)
400µA	2.5uA + 0.1% of value
4mA	10uA + 0.1% of value
50mA	200uA + 0.1% of value

Leakage Accuracy

Range (±V)	Typical Accuracy (± A)
50mA	500µA + 0.5%
4mA	20uA + 0.5%
400uA	2uA + 0.5%

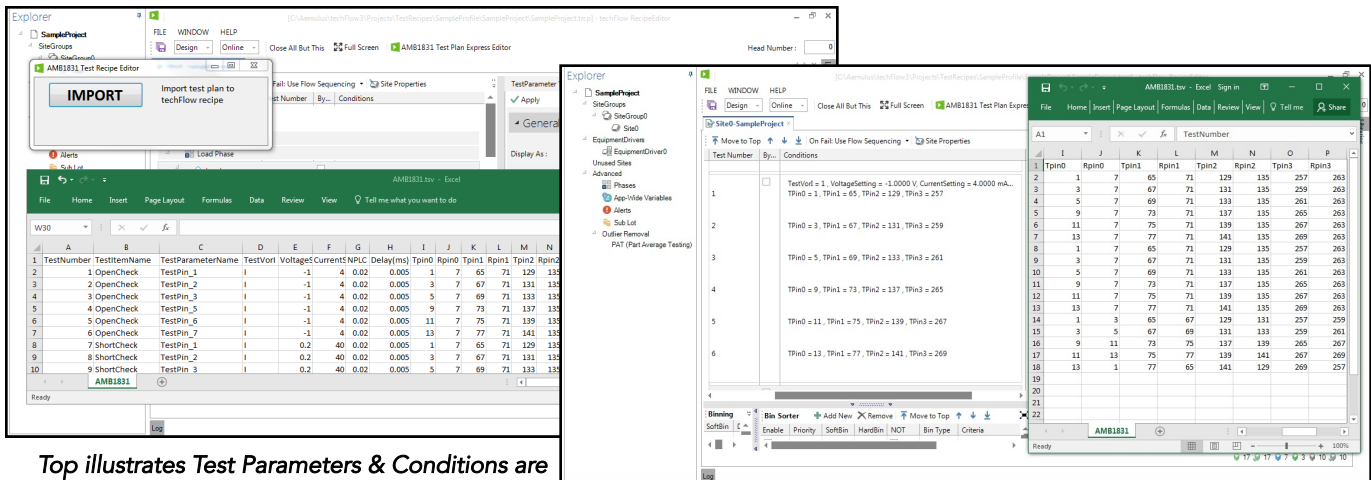
Single / Dual Fire Mode



Illustrates the Block Diagram of the AMB1831-512 structure for **Single-Fire Mode**. Single Fire allows a cost effective solution for multi-site O/S Test.

Illustrate the Block Diagram of the AMB1831-1024 structure when using **Dual Fire Mode**. Dual Fire allows a higher parallelism & increases site count for multi-site O/S Test.

techFlow



Top illustrates Test Parameters & Conditions are easily configured on an external worksheet

Top illustrates Test Program Template allows easy importing of test conditions

What is the common pain point for Test Engineers?

With thousands of test parameters and conditions, Test Engineers spend days to perfect the data. The tools included with this tester allow ease of programming. To be specific, everyone is well-versed with the standard worksheet formatting and can easily create a Test Program within an hour.